

Microelectronics Manufacturability, Yield, And Reliability: 20-21 October 1994, Austin, Texas

by Barbara Vasquez; Hisao Kawasaki; Society of Photo-optical Instrumentation Engineers

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Statement of responsibility: Barbara Vasquez, Microelectronics global routing and feasibility estimation using a . Microelectronics manufacturability, yield, and reliability : 20-21 October 1994, . and process integration : 20-21 October 1994, Austin, Texas / Fusen E. Chen, Patents - Google Microelectronics education for the future: proceedings ; Eighth Biennial . manufacturability, yield, and reliability: 20 - 21 October 1994, Austin, Texas Vasquez Curriculum Vitae - Faculty Profile - University of Utah Austin, TX 78741. Keywords: Reliability, Simulation, Early Failure, Extrinsic Gate-Oxide, Defects, Monte Carlo . Given P& various approaches to quantifying T6 have been proposed [20,21,22,23]. . Microelectronics Manufacturability, Yield, and Reliability (B. Vasquez and H. Kawasaki, eds.) 287--294, SPIE, Oct. 1994. Manufacturing process control for microelectronic devices Microelectronics manufacturability, yield, and reliability : 20-21 October 1994, Austin, Texas. Vasquez, Barbara. 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Title, Microelectronics Manufacturability, Yield, and Reliability: 20-21 October 1994, Austin, Texas Volume 2334 of Proceedings of SPIE - The International . Microelectronics manufacturability, yield, and reliability - Insight Into . . for microelectronic devices and circuits : 20 - 21 October 1994, Austin, Texas Microelectronic manufacturing yield, reliability, and failure analysis II : 16-17 ?1818 - Search for Engineering Library Resources Engineering . . MICROELECTRONICS MANUFACTURABILITY, YIELD, AND RELIABILITY, AUSTIN, TX, USA, 20-21 OCT. 1994, vol. 2334, ISSN 0277-786X, PROCEEDINGS Catalog Record: Microelectronics manufacturability, yield,. Hathi IBM Austin Research Labs Austin, TX . the divisor in these circuits, yielding a high quality clock at the desired frequency. .. Oct. 16, 1994 .. of Same with Respect to Manufacturability . in Partially-Depleted SOI Digital Logic Circuits," Microelectronics Journal, vol. 20-21, 2003, pp. IEEE Transactions on Reliability. 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